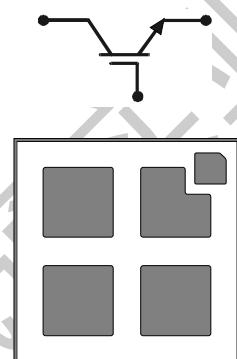


XPT IGBT Chip

Type	V _{CE} [V]	I _C [A]	Chip Size [mm] x [mm]	Package	Ordering Code
IX64X12A	1200	50	8.0 8.1	sawn on foil <input type="checkbox"/> unsawn wafer <input type="checkbox"/> in waffle pack <input checked="" type="checkbox"/>	- - tbd



Features / Advantages:

- Easy paralleling due to the positive temperature coefficient of the on-state voltage
- Rugged XPT design (Xtreme light Punch Through) results in:
 - short circuit rated for 10 μ sec.
 - very low gate charge
 - square RBSOA @ 3x I_C
 - low EMI
- Thin wafer technology combined with the XPT design results in a competitive low V_{ce(sat)}

Applications:

- AC motor drives
- Solar inverter
- Medical equipment
- Uninterruptible power supply
- Air-conditioning systems
- Welding equipment

Mechanical Parameters

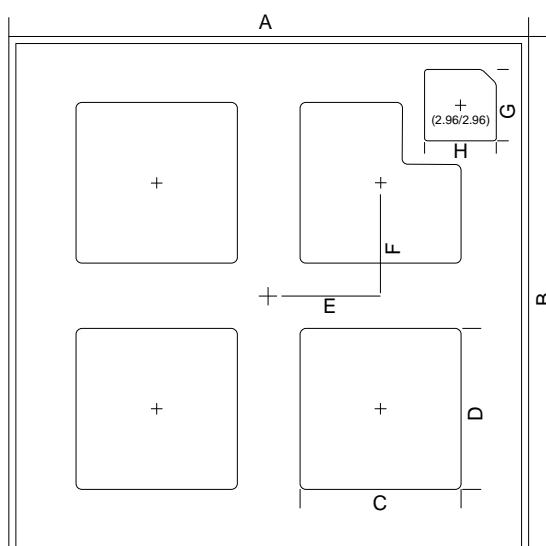
Parameters	Conditions	Ratings	Unit
Area active		47.68	mm ²
Area total		64.80	mm ²
Wafer size Ø		150	mm
Thickness		130	µm
Material	SiFZ	Orientation	<100>
Max. possible chips	per wafer		
Passivation	front side		SiN
Metalization	top side		AlSi
	backside		Al / Ti / Ni / Ag
Recom. wire bonds (Al)	Emitter	8 / 300	- / µm
	Gate	1 / 300	- / µm
Reject Ink Dot Size	Ø	0.4-1.0	mm
Recom. Storage Environment	in orig. container, in dry nitrogen	< 6	month
	Storage Temperature (T _{stg})	-40 ... 40	°C
Virtual junction temperature T _{vj}		-40 ... 150	°C

Electrical Parameters

Symbol	Definition	Conditions	Ratings			
			min.	typ.	max.	Unit
V_{CES}	Collector emitter voltage	$V_{GE} = 0 \text{ V}$ $I_C = 1 \text{ mA}$ $T_{VJ} = 25^\circ\text{C}$			1200	V
V_{GES}	Maximum DC gate voltage				± 20	V
I_c	Collector current (depending on thermal properties of assembly)			50		A
$V_{CE\text{ sat}}$	Collector emitter saturation voltage	$V_{GE} = 15 \text{ V}$ $I_C = 55 \text{ A}$ $T_{VJ} = 25^\circ\text{C}$ $T_{VJ} = 125^\circ\text{C}$		1.8	2.1	V
V_{TO}	Threshold voltage	$V_{GE} = 15 \text{ V}; T_{VJ} = 150^\circ\text{C}$			1.1	V
r_T	(for power loss calculation)				25.5	$\text{m}\Omega$
I_{CES}	Collector emitter leakage current	$V_{CE} = 1200 \text{ V}$ $V_{GE} = 0 \text{ V}$ $T_{VJ} = 25^\circ\text{C}$ $T_{VJ} = 125^\circ\text{C}$		10	100	μA
				100		μA
I_{GES}	Gate emitter leakage current	$V_{CE} = 0 \text{ V}$ $V_{GE} = \pm 20 \text{ V}$			500	nA
$V_{GE(\text{th})}$	Gate emitter threshold voltage	$I_C = 2 \text{ mA}$ $V_{CE} = V_{GE}$ $T_{VJ} = 25^\circ\text{C}$	5.4		6.5	V
Q_{Gon}	Total gate charge	$I_C = 50 \text{ A}$ $V_{CE} = 600 \text{ V}$ $V_{GE} = \pm 15 \text{ V}$		165		nC
$R_{G\text{ int}}$	Internal gate resistor					Ω
C_{ies}	Input capacitance			3.29		nF
C_{oes}	Output capacitance	$V_{CE} = 25 \text{ V}$ $V_{GE} = 0 \text{ V}$ $f = 1 \text{ MHz}$		294		pF
C_{res}	Reverse transfer capacitance			120		pF
$t_{d(on)}$	Turn-on delay time			70		ns
t_r	Current rise time			40		ns
$t_{d(off)}$	Turn-off delay time	$V_G = 600 \text{ V}$ $I_C = 50 \text{ A}$		250		ns
t_f	Current fall time	$R_G = 15 \Omega$ $V_{GE} = \pm 15 \text{ V}$ $T_{VJ} = 125^\circ\text{C}$		100		ns
E_{on}	Turn-on energy per pulse	measured with: DWHP 56-12B		4.5		mJ
E_{off}	Turn-off energy per pulse			5.5		mJ
RBSOA	Reverse bias safe operation area	$V_{GE} = 15 \text{ V}$ $R_G = 15 \Omega$ $T_{VJ} = 125^\circ\text{C}$ $V_{CE} = 1200 \text{ V}$			150	A
SCSOA	Short circuit safe operation area					
t_{sc}	Short circuit duration	$V_{CE} = 900 \text{ V}$ $V_{GE} = \pm 15 \text{ V}$ $T_{VJ} = 125^\circ\text{C}$			10	μs
I_{sc}	Short circuit current	$R_G = 15 \Omega$ non-repetitive			200	A

Data according to IEC 60747

Dimensions (1 mm = 0.0394")



A [mm]	B [mm]	C [mm]	D [mm]	E [mm]
8.0	8.1	2.5	2.5	1.75

F [mm]	G [mm]	H [mm]	I [mm]	J [mm]
1.75	1.1	1.1	n/a	n/a

